

Docket No.: 60188-725

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Customer Number: 20277
Mitsuyasu OHTA, et al. : Confirmation Number:
Serial No.: Continuation of Appl. No.
09/381,377 : Group Art Unit:
Filed: January 06, 2004 : Examiner:
For: FUNCTIONAL BLOCK FOR INTEGRATED CIRCUIT, SEMICONDUCTOR
INTEGRATED CIRCUIT, METHOD FOR TESTING SEMICONDUCTOR
INTEGRATED CIRCUIT, AND METHOD FOR DESIGNING SEMICONDUCTOR
INTEGRATED CIRCUIT

PRELIMINARY AMENDMENT

Mail Stop Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Prior to examination of the above-referenced application, please amend the application as follows: